Search	Notes
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,901	HIROHATA ET AL.
Examiner	Art Unit

2815

Joseph Nguyen

SEARCHED					
Class	Subclass	Date	Examiner		
257	10	1/14/2005	JN		
257	81,99	1/14/2005	JN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
257	10	1/14/2005	JN		
257	81,99	1/14/2005	JN		
		-			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST	1/14/2005	JN
(photocathode) and (semiconductor)	1/14/2005	JN
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